

Sukeshwar Kannan

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9147708/publications.pdf>

Version: 2024-02-01

5
papers

58
citations

2682572

2
h-index

2550090

3
g-index

5
all docs

5
docs citations

5
times ranked

34
citing authors

#	ARTICLE	IF	CITATIONS
1	Built-in Self-Test and Fault Localization for Inter-Layer Vias in Monolithic 3D ICs. ACM Journal on Emerging Technologies in Computing Systems, 2022, 18, 1-37.	2.3	2
2	A Design-for-Test Solution Based on Dedicated Test Layers and Test Scheduling for Monolithic 3-D Integrated Circuits. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2019, 38, 1942-1955.	2.7	10
3	Impact of Electrostatic Coupling and Wafer-Bonding Defects on Delay Testing of Monolithic 3D Integrated Circuits. ACM Journal on Emerging Technologies in Computing Systems, 2017, 13, 1-23.	2.3	28
4	A Design-for-Test Solution for Monolithic 3D Integrated Circuits. , 2017, , .		8
5	Impact of wafer-bonding defects on Monolithic 3D integrated circuits. , 2016, , .		10